

Maximum Ratings (@T_A = +25°C, unless otherwise specified.)

Characteristic			Symbol	Q1 Value	Q2 Value	Units
Drain-Source Voltage			V _{DSS}	12	-12	V
Gate-Source Voltage			V _{GSS}	±8	±8	V
Continuous Drain Current (Note 5) V _{GS} = 4.5V	Steady State	T _A = +25°C T _A = +70°C	I _D	9.5 7.6	-6.9 -5.5	A
	t < 10s	T _A = +25°C T _A = +70°C	I _D	13.0 10.4	-9.4 -7.5	A
Maximum Body Diode Forward Current			I _S	2	-2	A
Pulsed Drain Current (10μs pulse, duty cycle = 1%)			I _{DM}	50	-35	A
Avalanche Current (Note 6) L = 0.1mH			I _{AS}	9.7	-9.2	A
Avalanche Energy (Note 6) L = 0.1mH			E _{AS}	4.7	4.3	mJ

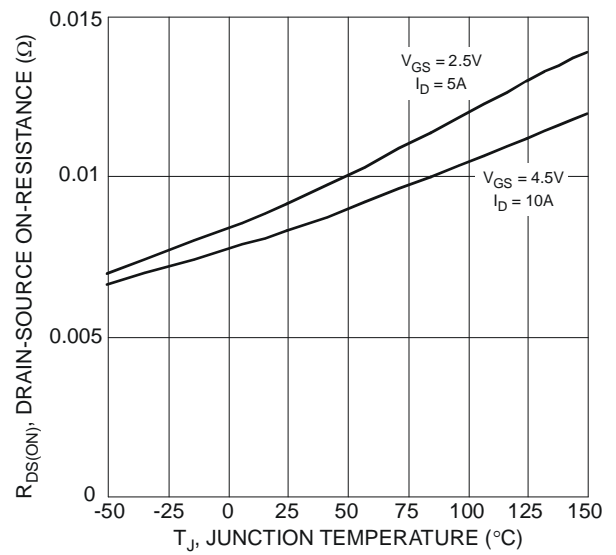
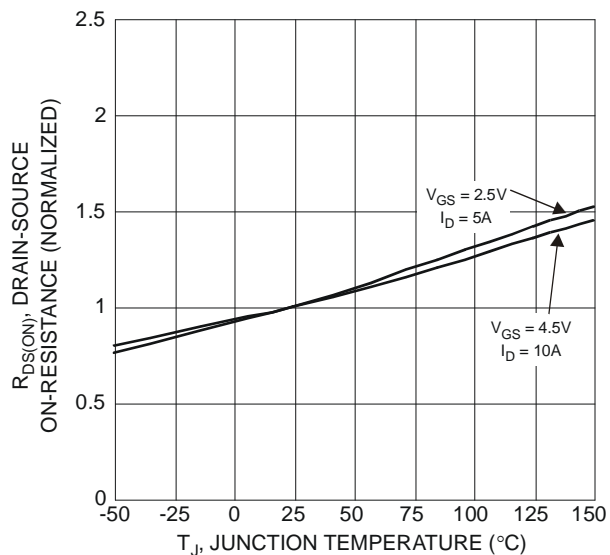
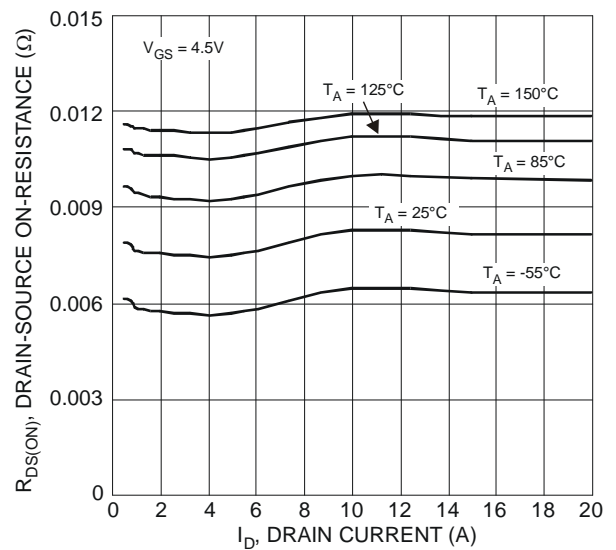
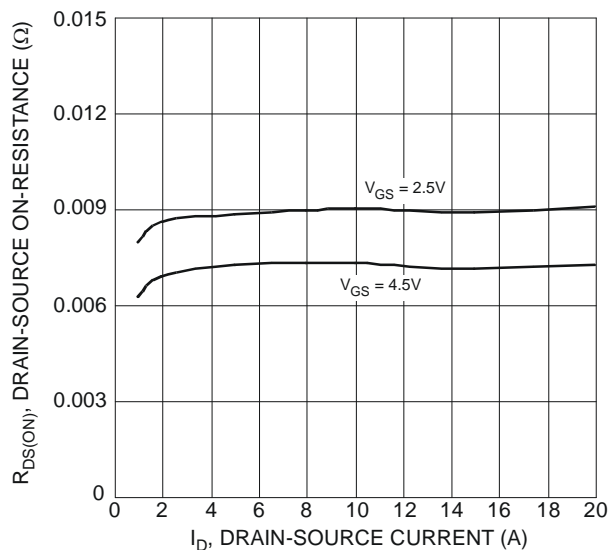
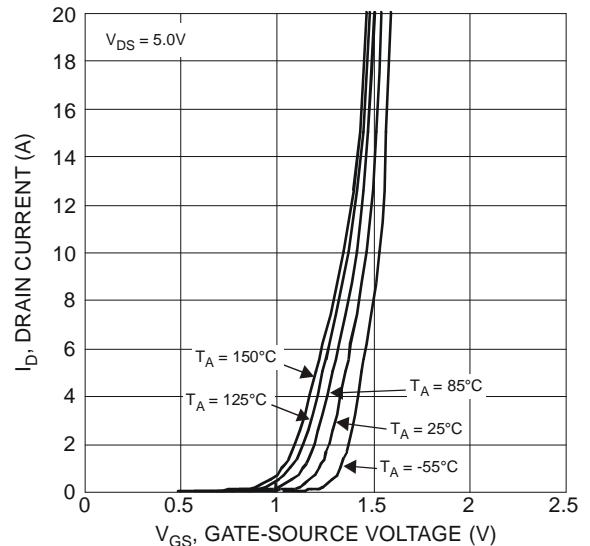
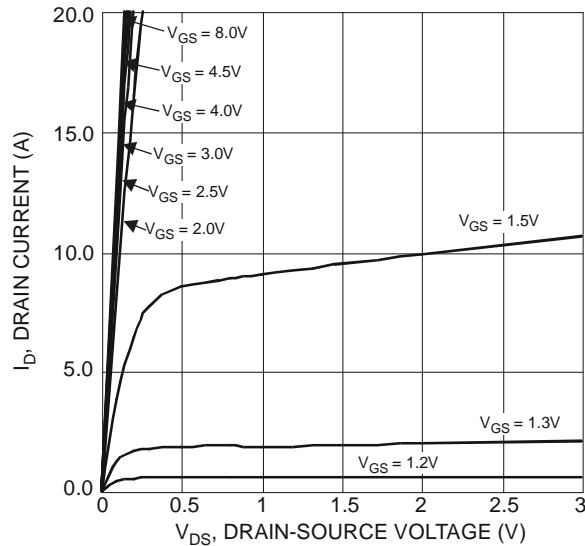
Thermal Characteristics

Characteristic		Symbol	Value	Units
Total Power Dissipation (Note 5)	T _A = +25°C	P _D	2.3	W
	T _A = +70°C		1.5	
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	R _{θJA}	54	°C/W
	t < 10s		29	
Thermal Resistance, Junction to Case (Note 5)		R _{θJC}	4.1	
Operating and Storage Temperature Range		T _J , T _{STG}	-55 to +150	°C

Electrical Characteristics Q1 N-Channel (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	12	—	—	V	V _{GS} = 0V, I _D = 250μA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	1	μA	V _{DS} = 12V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±8V, V _{DS} = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(th)}	0.6	—	1.5	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	9.6	17	mΩ	V _{GS} = 4.5V, I _D = 11.8A
		—	11	25		V _{GS} = 2.5V, I _D = 9.8A
Diode Forward Voltage	V _{SD}	—	0.7	1.2	V	V _{GS} = 0V, I _S = 2.9A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	—	1787	—	pF	V _{DS} = 6V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{oss}	—	297	—		
Reverse Transfer Capacitance	C _{rss}	—	265	—		
Gate Resistance	R _G	—	1.6	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1.0MHz
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	18.6	—	nC	V _{DS} = 6V, I _D = 11.8A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	35.4	—		
Gate-Source Charge	Q _{gs}	—	2.7	—		
Gate-Drain Charge	Q _{gd}	—	3.8	—		
Turn-On Delay Time	t _{p(on)}	—	6.9	—	nS	V _{DD} = 6V, R _L = 6Ω V _{GS} = 4.5V, R _G = 6Ω, I _D = 1A
Turn-On Rise Time	t _r	—	10.9	—		
Turn-Off Delay Time	t _{p(off)}	—	70.3	—		
Turn-Off Fall Time	t _f	—	31.8	—		
Body Diode Reverse Recovery Time	t _{rr}	—	13.1	—	nS	I _F = 11.8A, di/dt = 100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	—	2.2	—	nC	I _F = 11.8A, di/dt = 100A/μs

- Notes:
5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
 6. I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep T_J = 25°C.
 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to product testing.



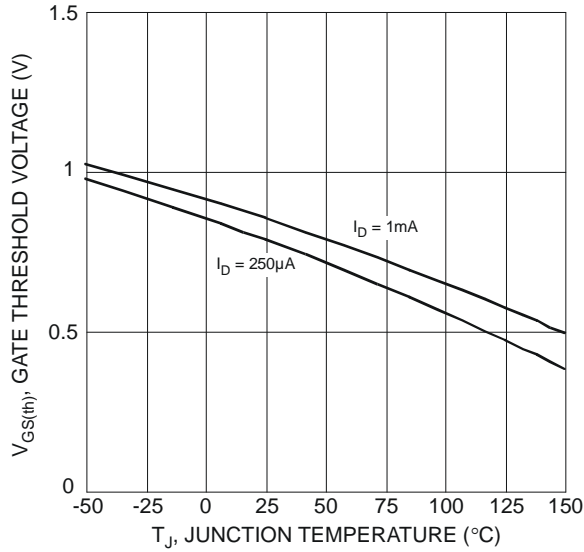


Figure 7 Gate Threshold Variation vs. Ambient Temperature

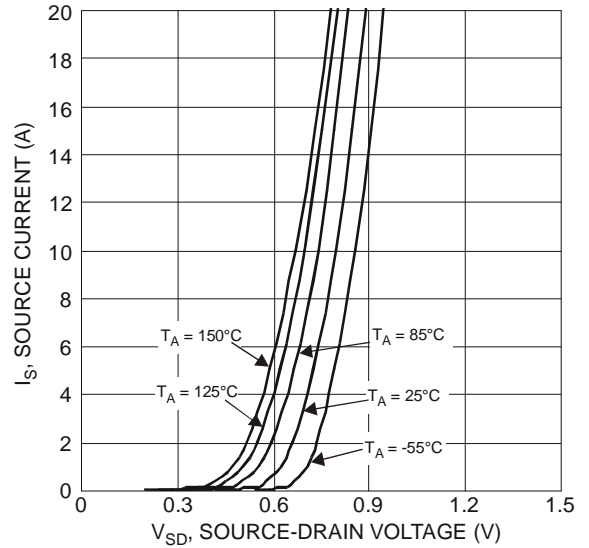


Figure 8 Diode Forward Voltage vs. Current

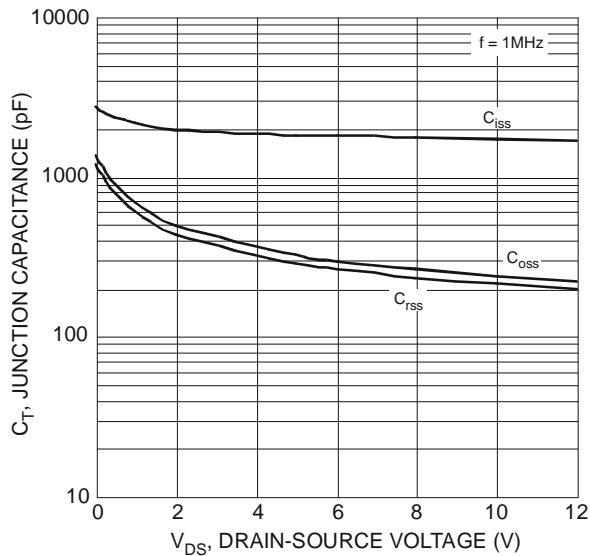


Figure 9 Typical Junction Capacitance

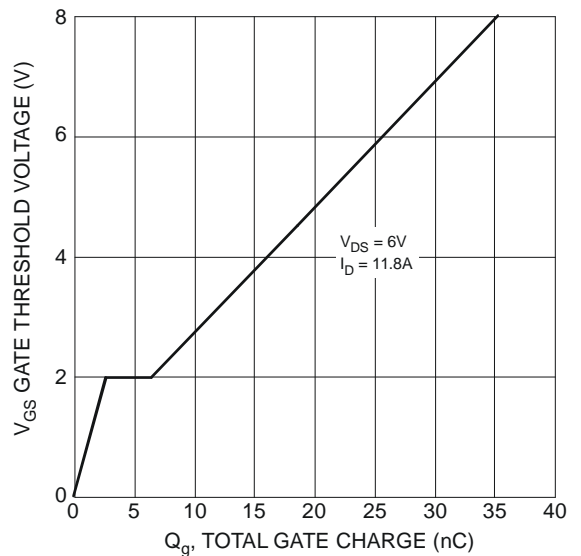
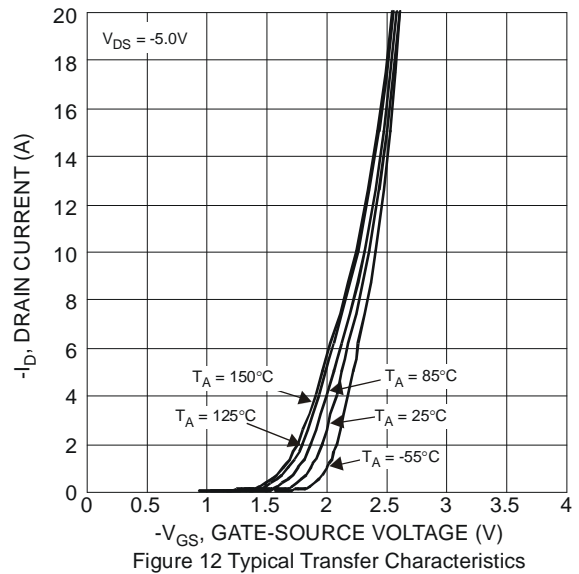
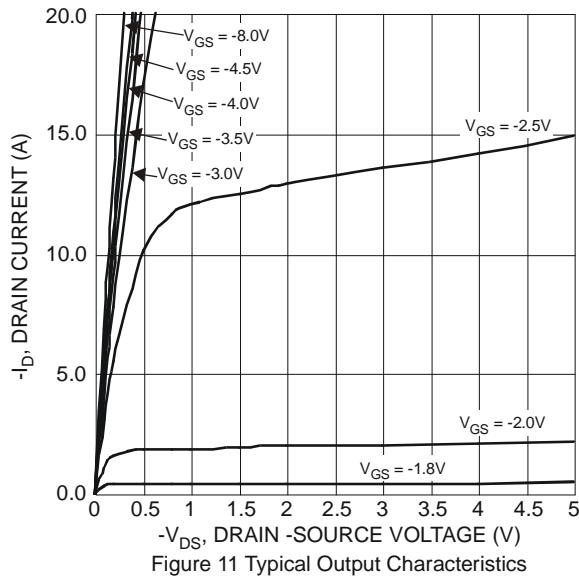


Figure 10 Gate Charge

Electrical Characteristics Q2 P-Channel (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 6)						
Drain-Source Breakdown Voltage	BV _{DSS}	-12	—	—	V	V _{GS} = 0V, I _D = -250μA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	-1	μA	V _{DS} = -12V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±8V, V _{DS} = 0V
ON CHARACTERISTICS (Note 6)						
Gate Threshold Voltage	V _{GS(th)}	-0.6	—	-1.5	V	V _{DS} = V _{GS} , I _D = -250μA
Static Drain-Source On-Resistance	R _{DS(on)}	—	21	32	mΩ	V _{GS} = -4.5V, I _D = -8.9A
		—	41	53		V _{GS} = -2.5V, I _D = -6.9A
Diode Forward Voltage	V _{SD}	—	-0.7	-1.2	V	V _{GS} = 0V, I _S = -2.9A
DYNAMIC CHARACTERISTICS (Note 7)						
Input Capacitance	C _{iss}	—	2100	—	pF	V _{DS} = -6V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{oss}	—	872	—		
Reverse Transfer Capacitance	C _{rss}	—	626	—		
Gate Resistance	R _G	—	23.1	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1.0MHz
Total Gate Charge (V _{GS} = -4.5V)	Q _g	—	23.7	—	nC	V _{DS} = -6V, I _D = -8.9A
Total Gate Charge (V _{GS} = -8V)	Q _g	—	38.8	—		
Gate-Source Charge	Q _{gs}	—	5.3	—		
Gate-Drain Charge	Q _{gd}	—	9.8	—		
Turn-On Delay Time	t _{D(on)}	—	10.6	—	nS	V _{DD} = -6V, R _L = 6Ω V _{GS} = -4.5V, R _G = 6Ω, I _D = -1A
Turn-On Rise Time	t _r	—	25.5	—		
Turn-Off Delay Time	t _{D(off)}	—	144	—		
Turn-Off Fall Time	t _f	—	129	—		
Body Diode Reverse Recovery Time	t _{rr}	—	48.9	—	nS	I _F = -8.9A, di/dt = -100A/μs
Body Diode Reverse Recovery Charge	Q _{rr}	—	15.3	—	nC	I _F = -8.9A, di/dt = -100A/μs

Notes: 6. I_{AS} and E_{AS} rating are based on low frequency and duty cycles to keep T_J = 25°C.
7. Short duration pulse test used to minimize self-heating effect.



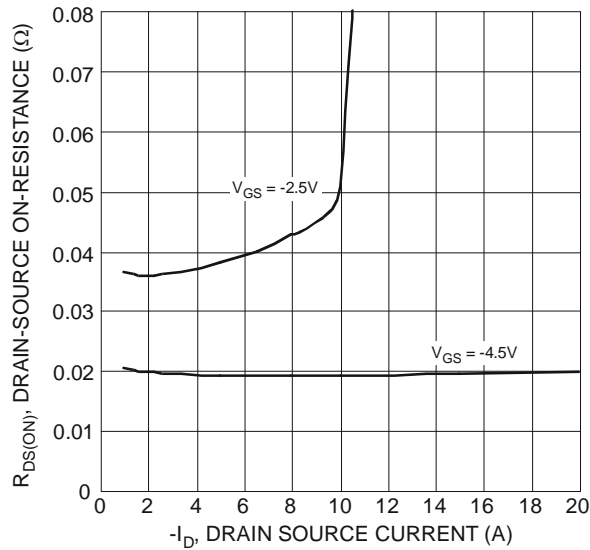


Figure 13 Typical On-Resistance vs. Drain Current and Gate Voltage

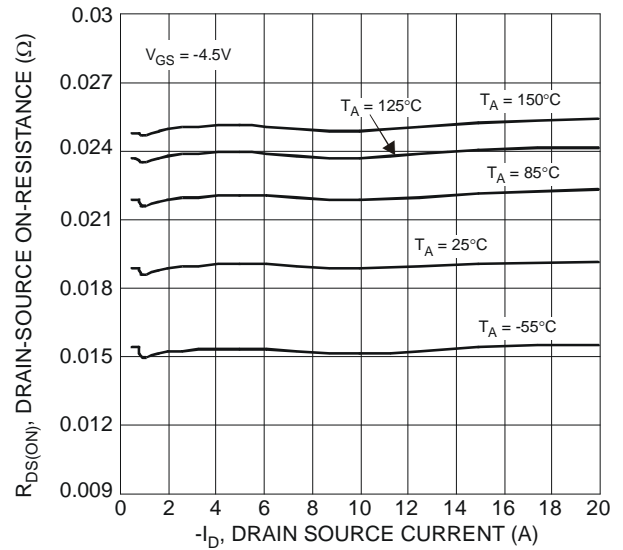


Figure 14 Typical On-Resistance vs. Drain Current and Temperature

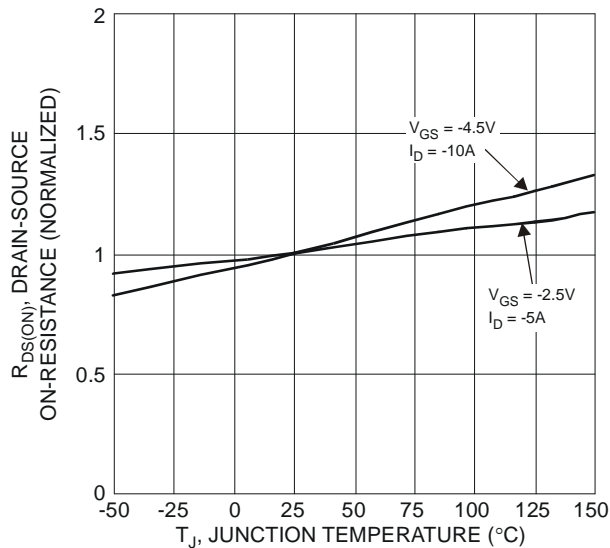


Figure 15 On-Resistance Variation with Temperature

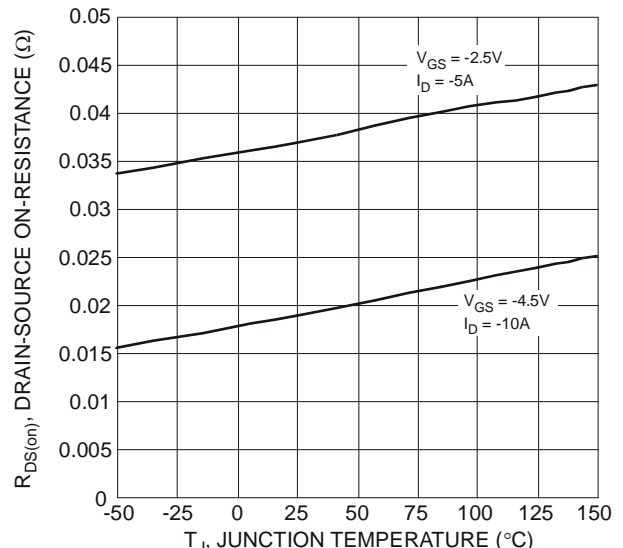


Figure 16 On-Resistance Variation with Temperature

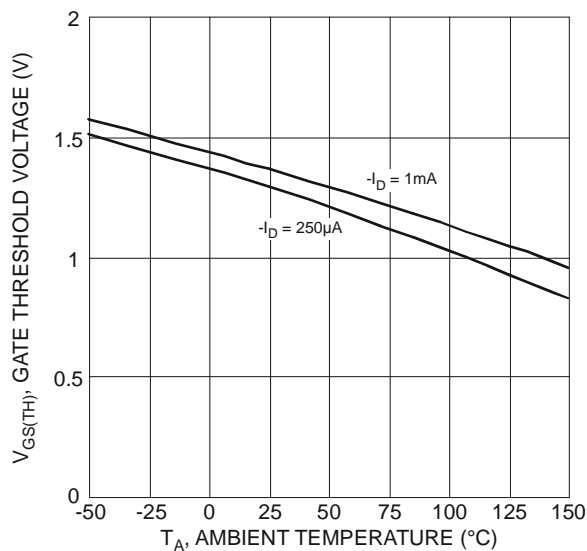


Figure 17 Gate Threshold Variation vs. Ambient Temperature

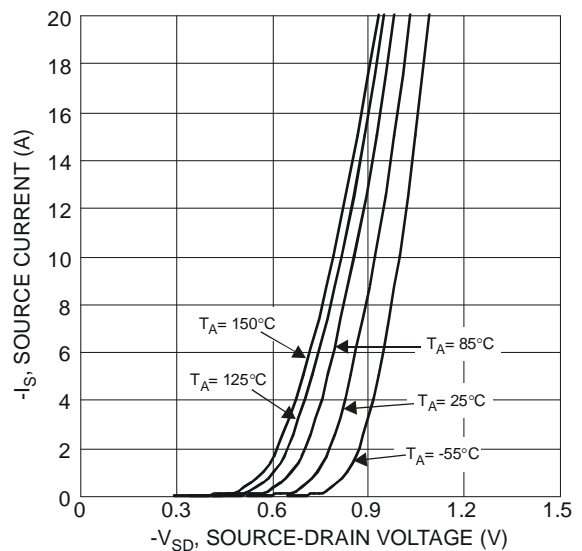
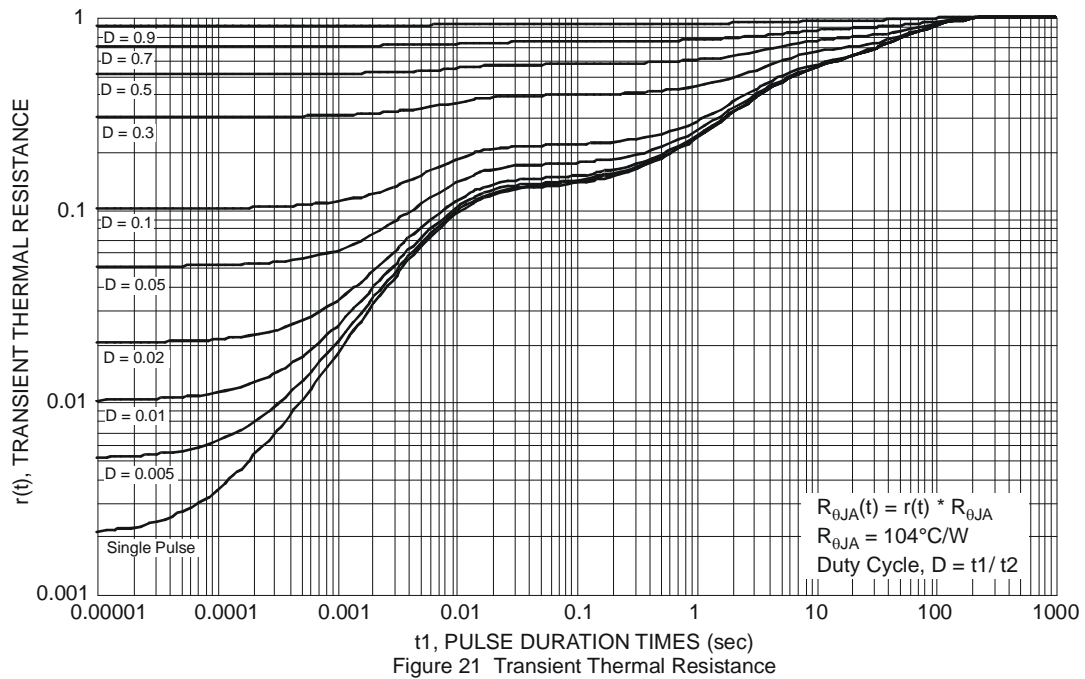
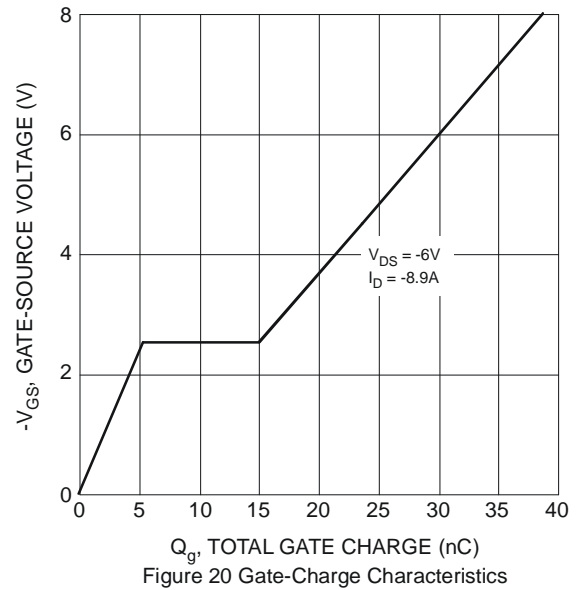
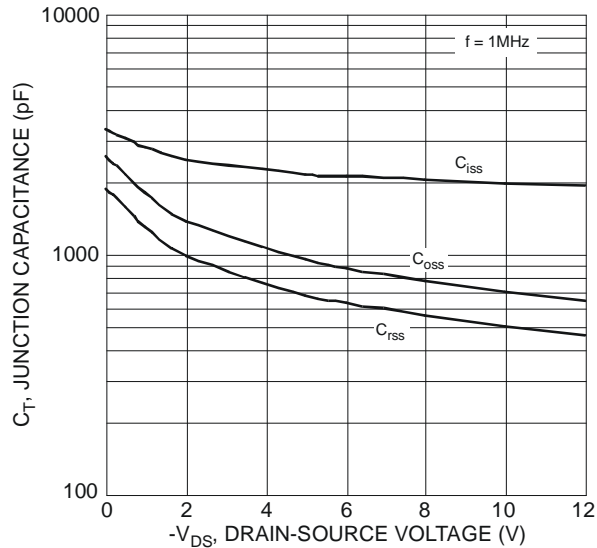
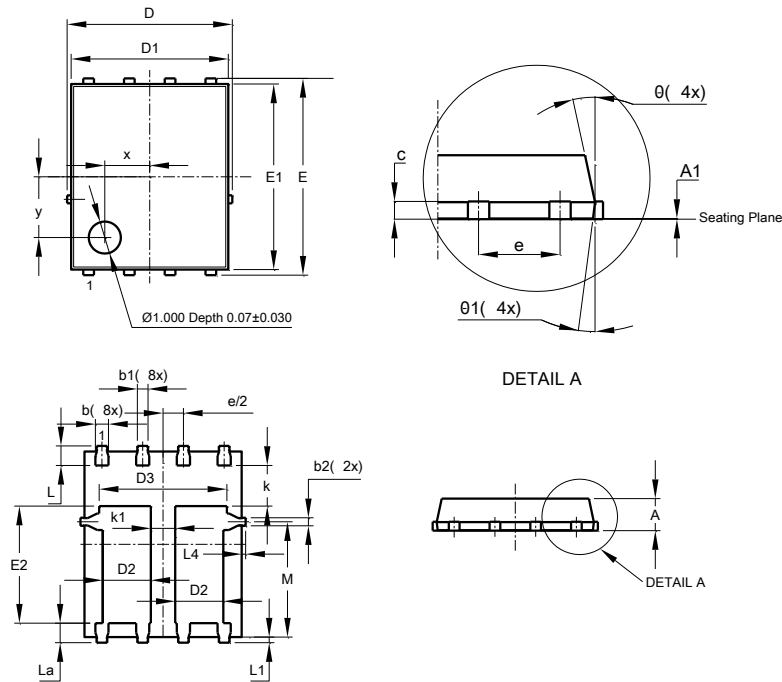


Figure 18 Diode Forward Voltage vs. Current



Package Outline Dimensions

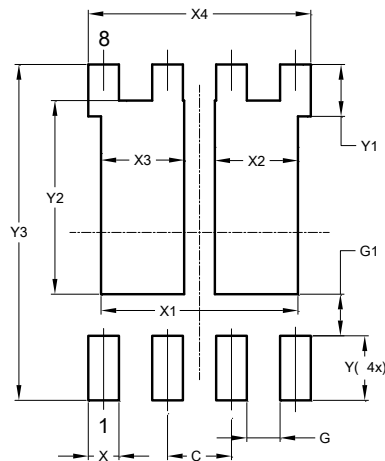
Please see AP02002 at <http://www.diodes.com/datasheets/ap02002.pdf> for latest version.



PowerDI5060-8			
Dim	Min	Max	Typ
A	0.90	1.10	1.00
A1	0	0.05	0.02
b	0.33	0.51	0.41
b1	0.300	0.366	0.333
b2	0.20	0.35	0.25
c	0.23	0.33	0.277
D	5.15 BSC		
D1	4.85	4.95	4.90
D2	1.40	1.60	1.50
D3	-	-	3.98
E	6.15 BSC		
E1	5.75	5.85	5.80
E2	3.56	3.76	3.66
e	1.27BSC		
k	-	-	1.27
k1	0.56	-	-
L	0.51	0.71	0.61
La	0.51	0.71	0.61
L1	0.05	0.20	0.175
L4	-	-	0.125
M	3.50	3.71	3.605
x	-	-	1.400
y	-	-	1.900
θ	10°	12°	11°
θ1	6°	8°	7°
All Dimensions in mm			

Suggested Pad Layout

Please see AP02001 at <http://www.diodes.com/datasheets/ap02001.pdf> for latest version.



Dimensions	Value (in mm)
C	1.270
G	0.660
G1	0.820
X	0.610
X1	3.910
X2	1.650
X3	1.650
X4	4.420
Y	1.270
Y1	1.020
Y2	3.810
Y3	6.610

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